

- Supplementary Information -

Metal halide perovskite layers studied by Scanning transmission X-ray microscopy

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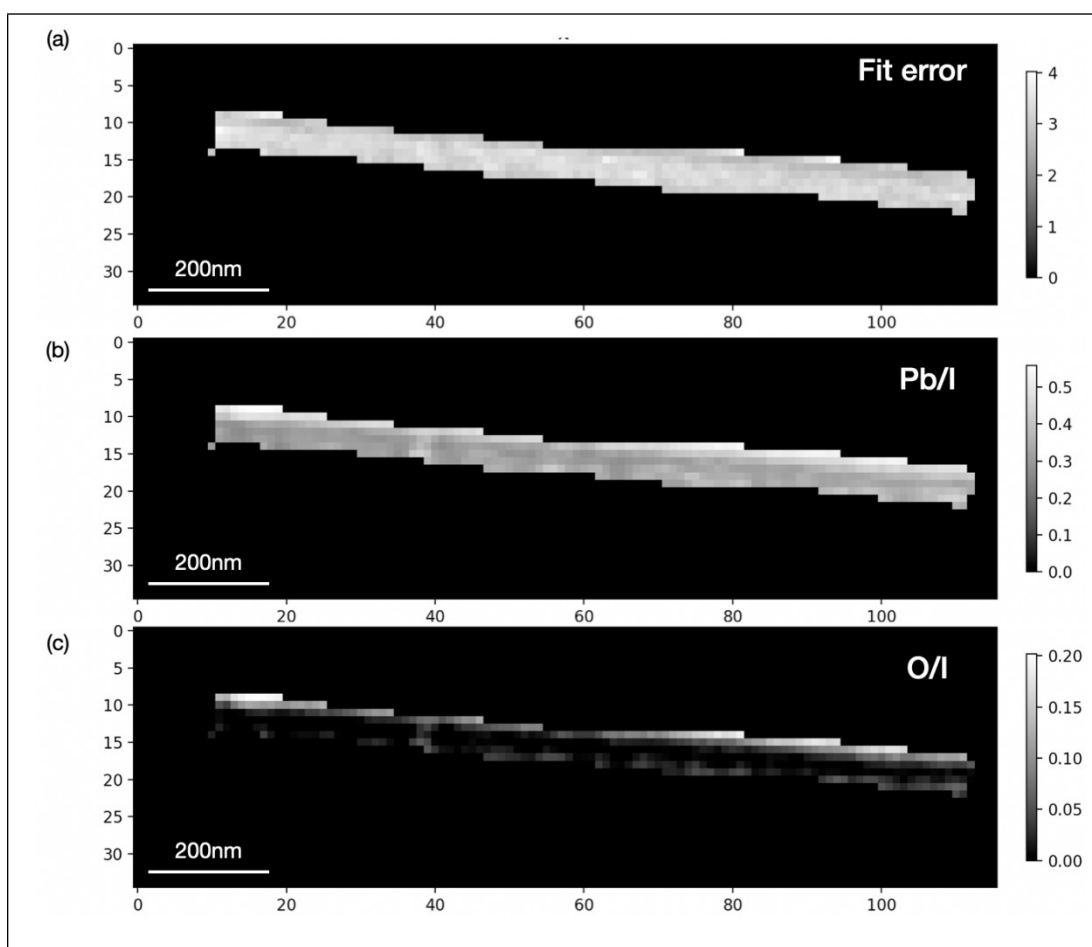


Figure S1: Map representing the (a) pixelwise fitting %age error (b) Pb/I ratio (c) O/I ratio for the unbiased sample

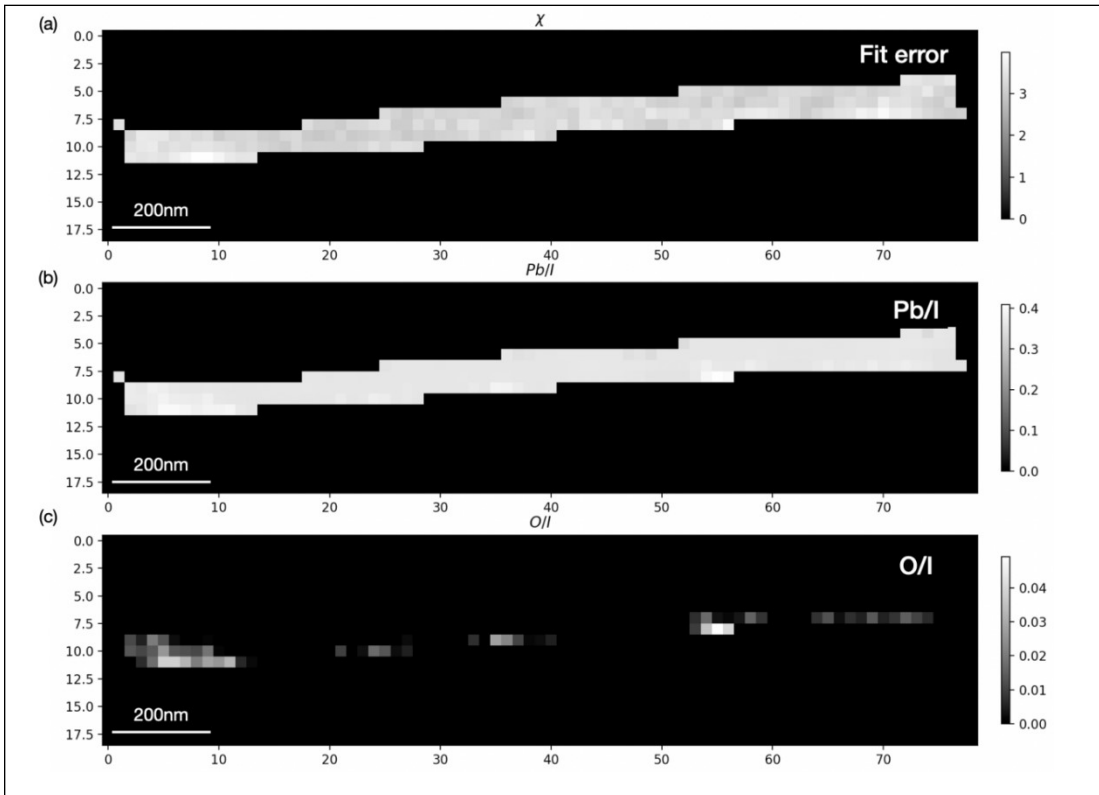


Figure S2: Map representing the (a) pixelwise fitting %age error (b) Pb/I ratio (c) O/I ratio for the biased sample

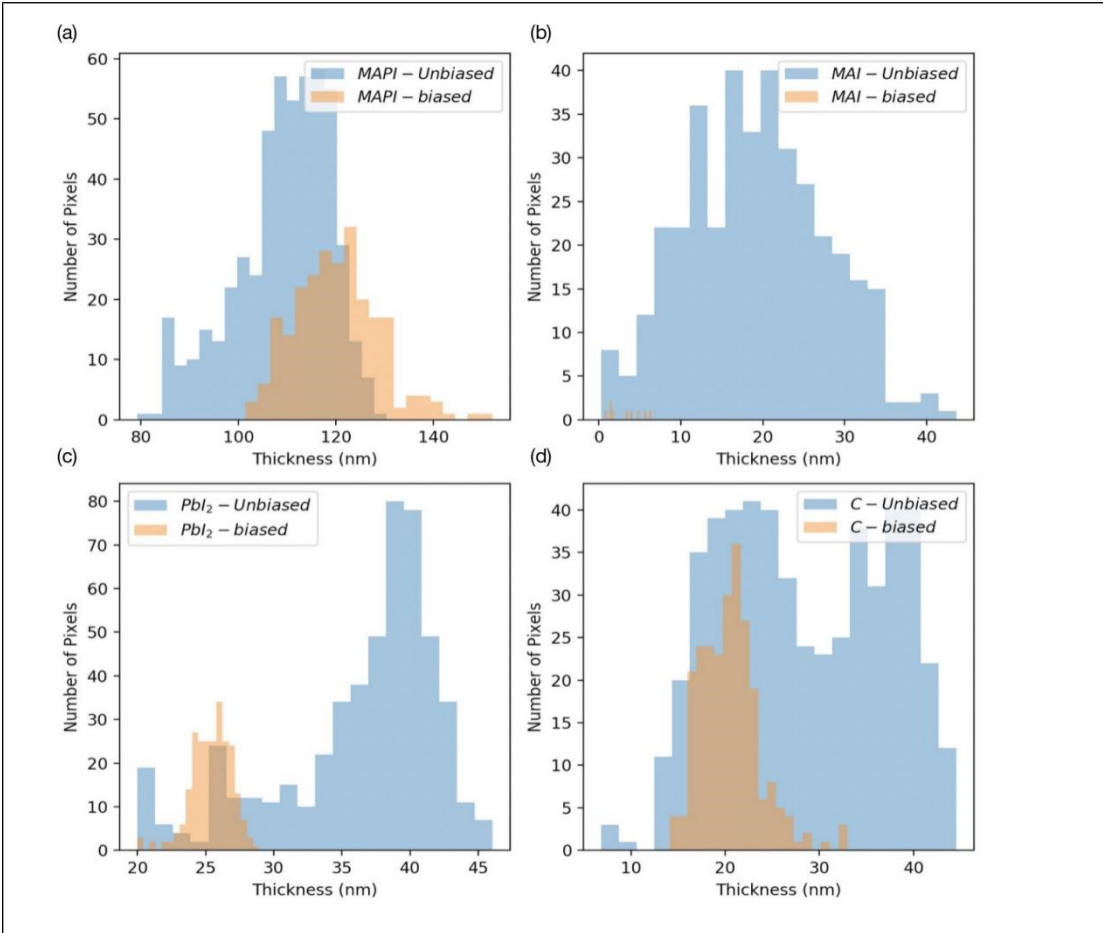


Figure S3: Histogram plots comparing the distribution in thickness values of fitted components (a) MAPbI₃ (b) MAI (c) PbI₂ and (d) Carbon for the unbiased and biased sample

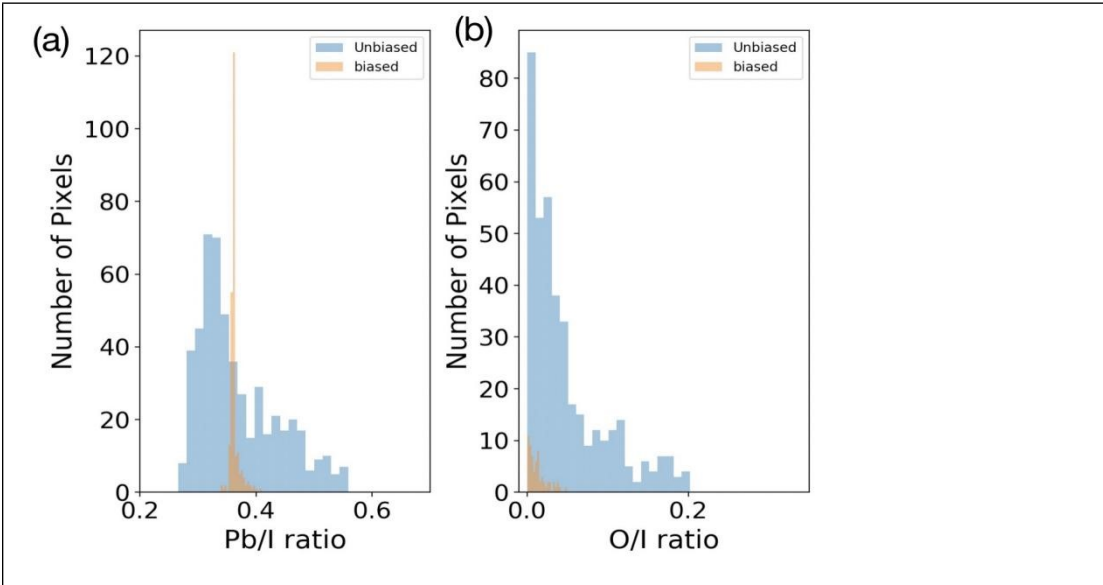


Figure S4: Histogram plots comparing the distribution in (a) Pb/I and (b) O/I values for the unbiased and biased samples